

Spurious Signals on the MSD Strips

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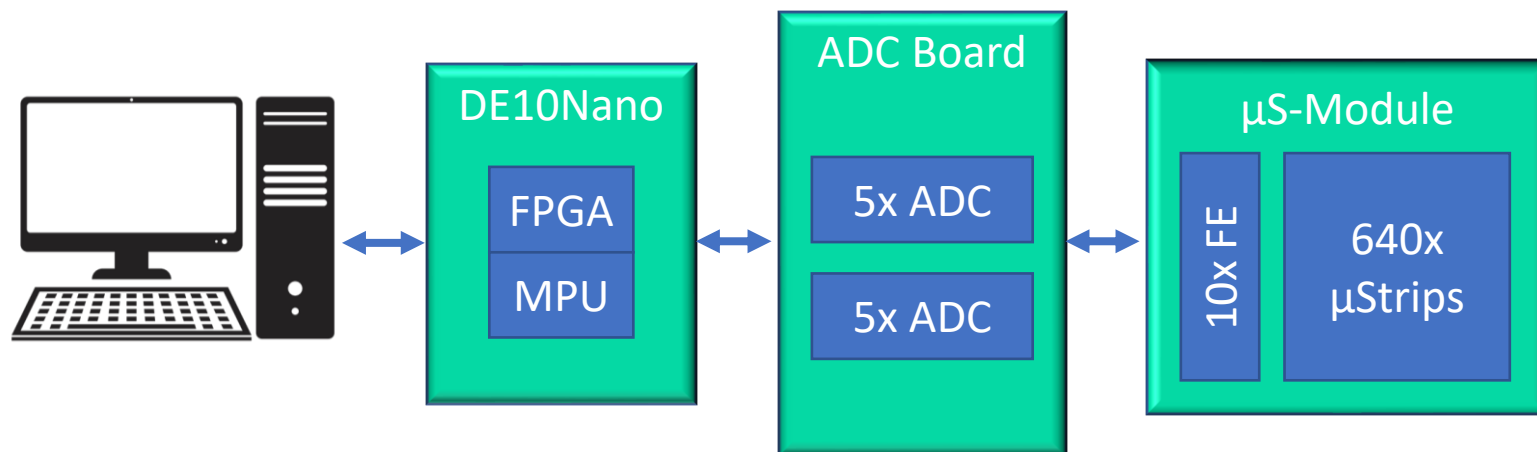


1. Recap on the MSD architecture and setup
2. Problem description
 - Spurious signals in the last VAs channels
3. Addressing of the problem
 - ADC sampling time
 - Reset of the digital circuitry of VAs
4. Verification: Calibration
5. Verification: Laser Setup



Recap on the MSD Architecture

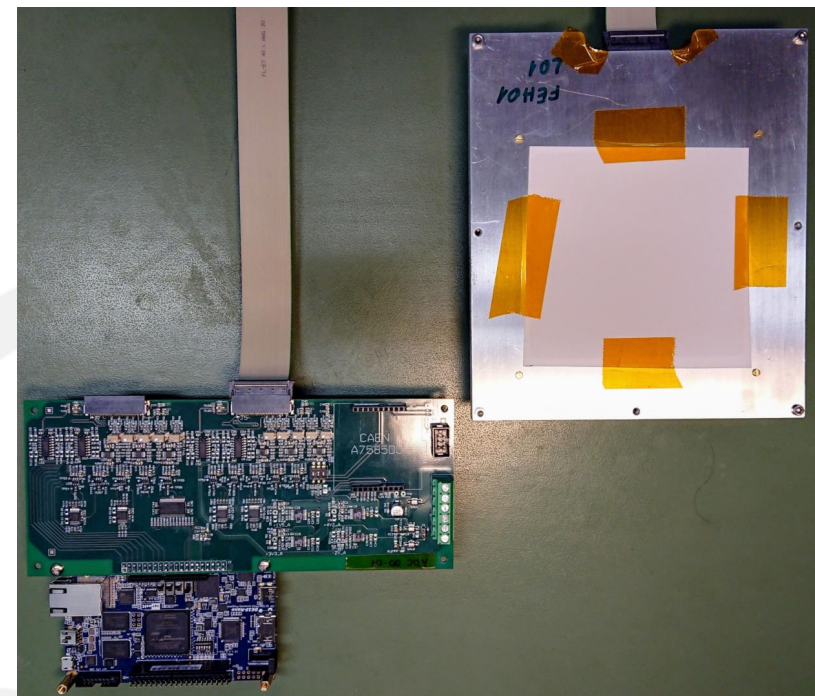
Single μ Strip Detector (MSD)



- 1x μ Strip Detector (L13):

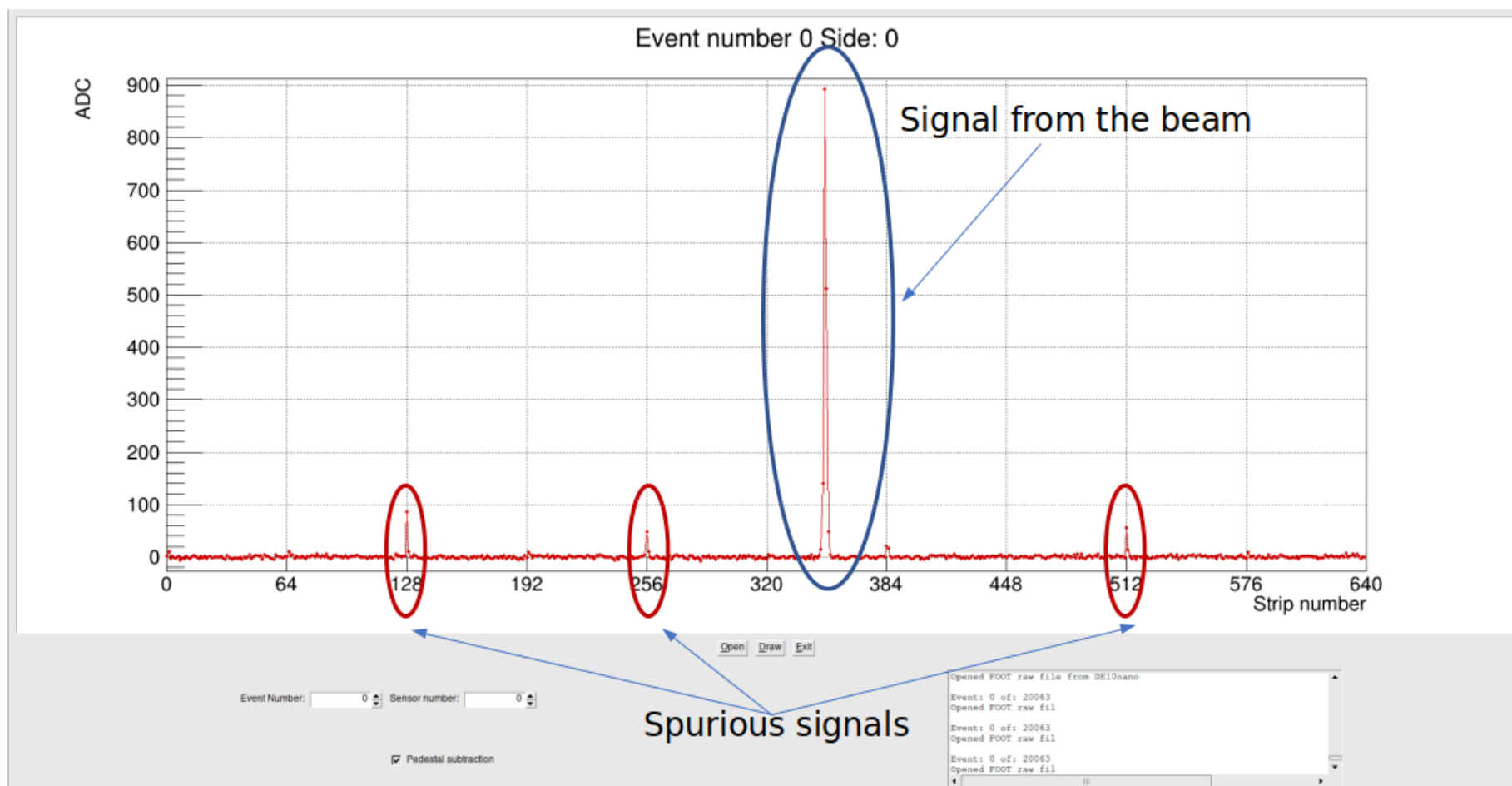
 - 10x IDE1140 front-ends (VAs)

- 1x ADC Board:
 - 10x AD7276 ADCs
- 1x DE10Nano: data acquisition



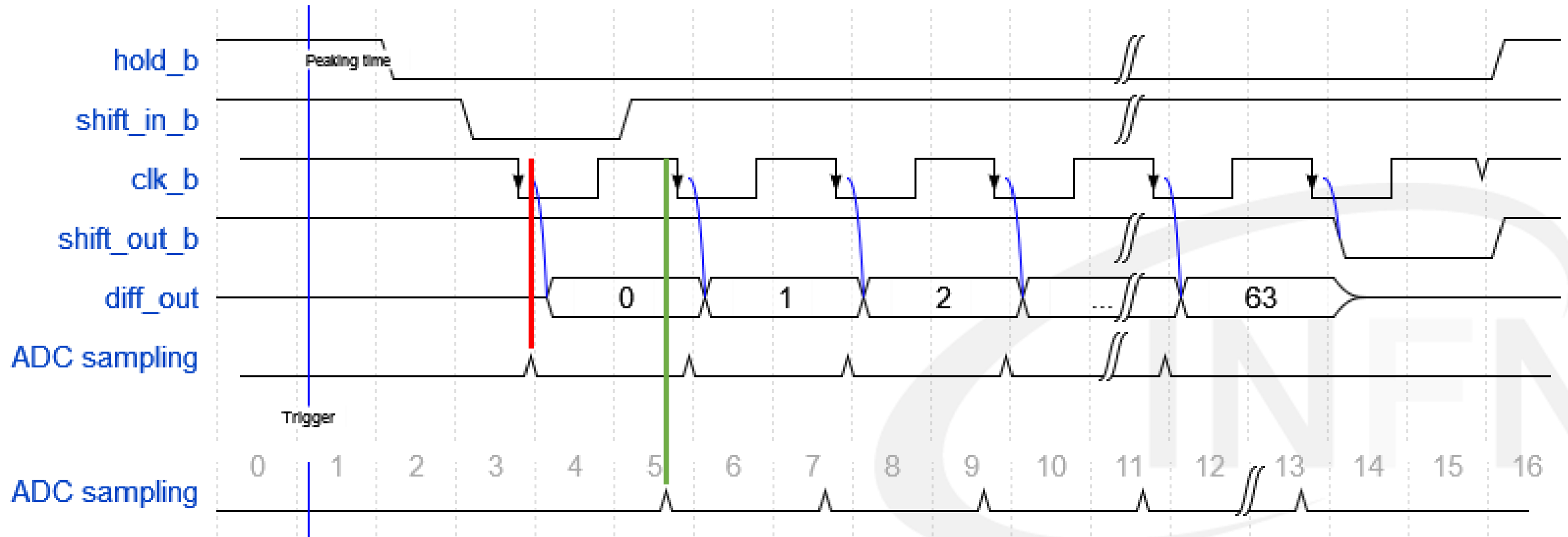
Spurious signals in the last VAs channels

RECAP: From last test beam we spotted these spurious signals in the last channels of the VAs



Sampling the strips analog signals too early

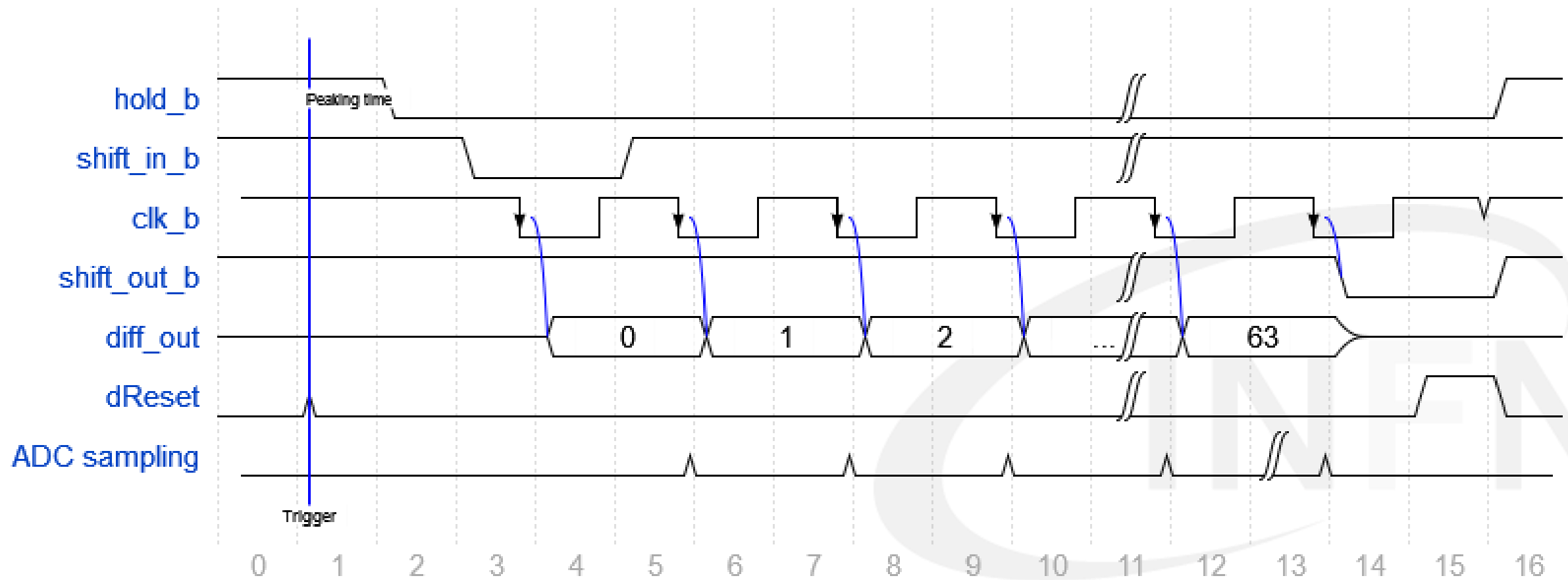
- GOAL: Sample one strip just before the consecutive one
- Delay the sampling time of a parametrizable value



Second possible cause: Reset

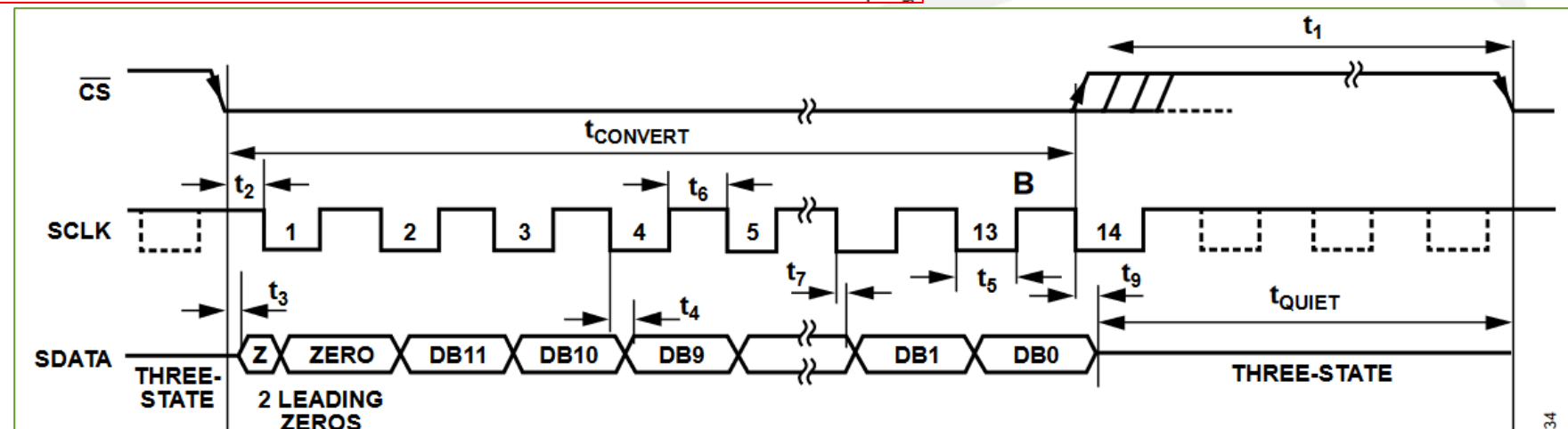
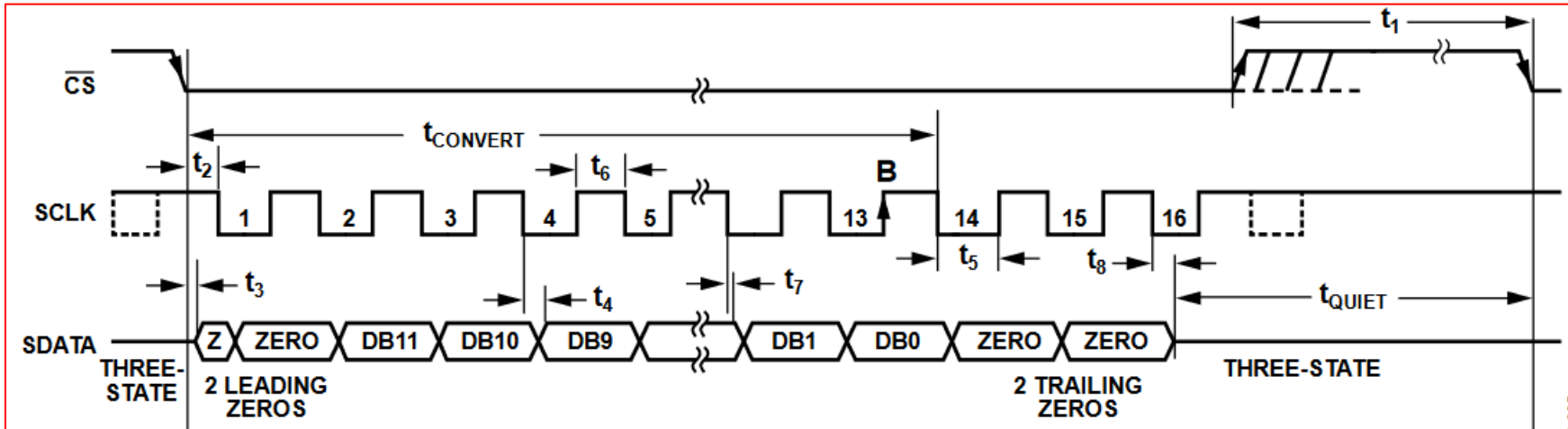
Digital circuitry of VAs need 65 clock cycles or reset

- We were sending 64 clocks per VA -> Added a Reset at beginning and end of a transaction



Reduce ADC conversion time by using AD7276 ADC *Fast-Mode*

- From 16 to 14 clock cycles -> 12.5% faster



1. Calibration of the system with the old GateWare (GW) as reference
2. Coarse scan to find the optimal ADC sampling delay
 - VA *clk_b* period: 800 ns
 - Delay values: 40, 200, 400, 600, and 700 ns
3. Calibrations with *dReset* assertion at different moments
 - No dReset, end of read-out, beginning and end of read-out
4. Laser beam to see spurious signals

Calibration: 5000 events (without source) to compute

- Average
- Raw-sigma
- Sigma

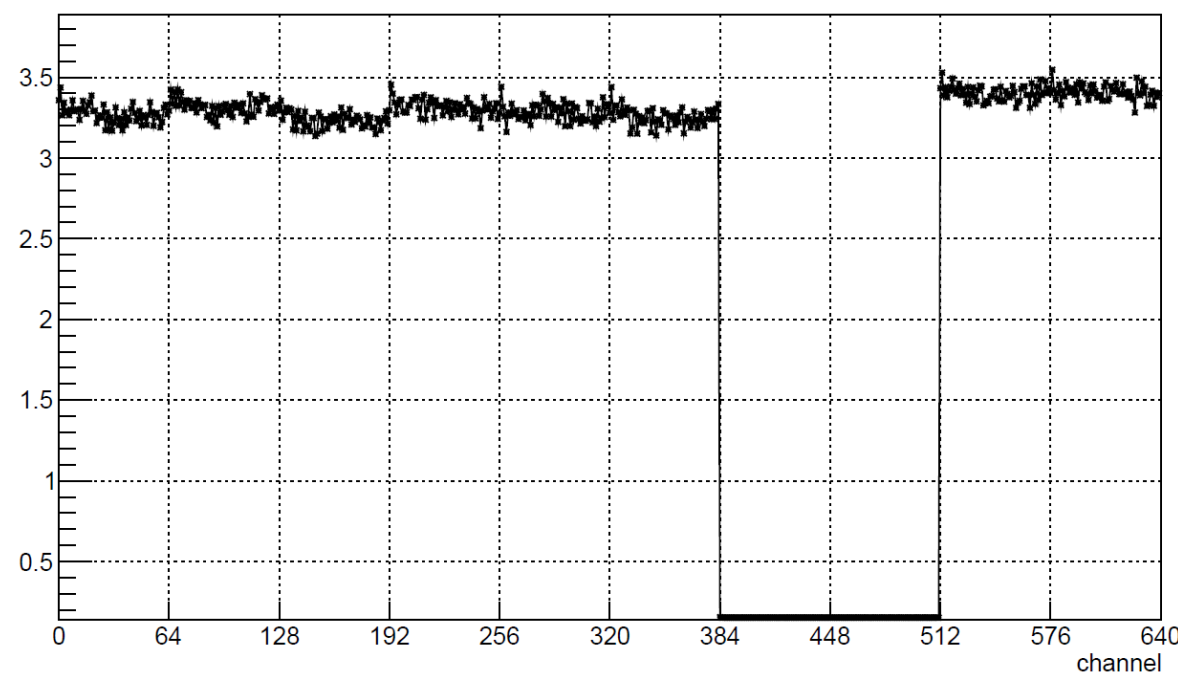
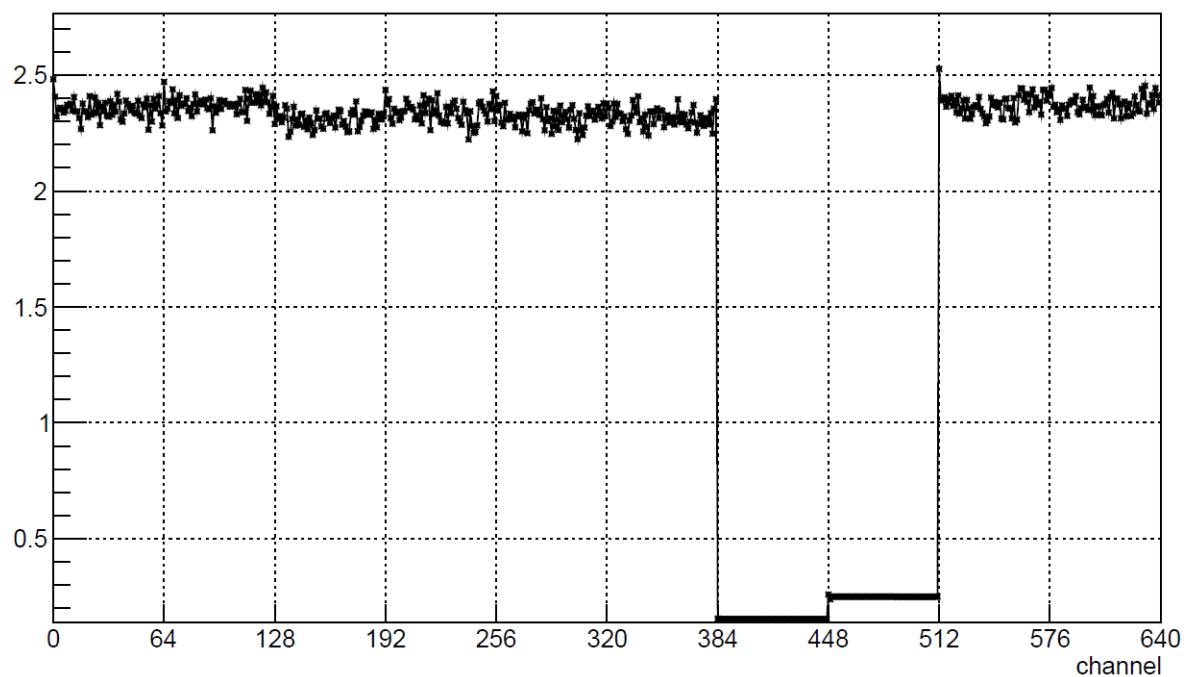
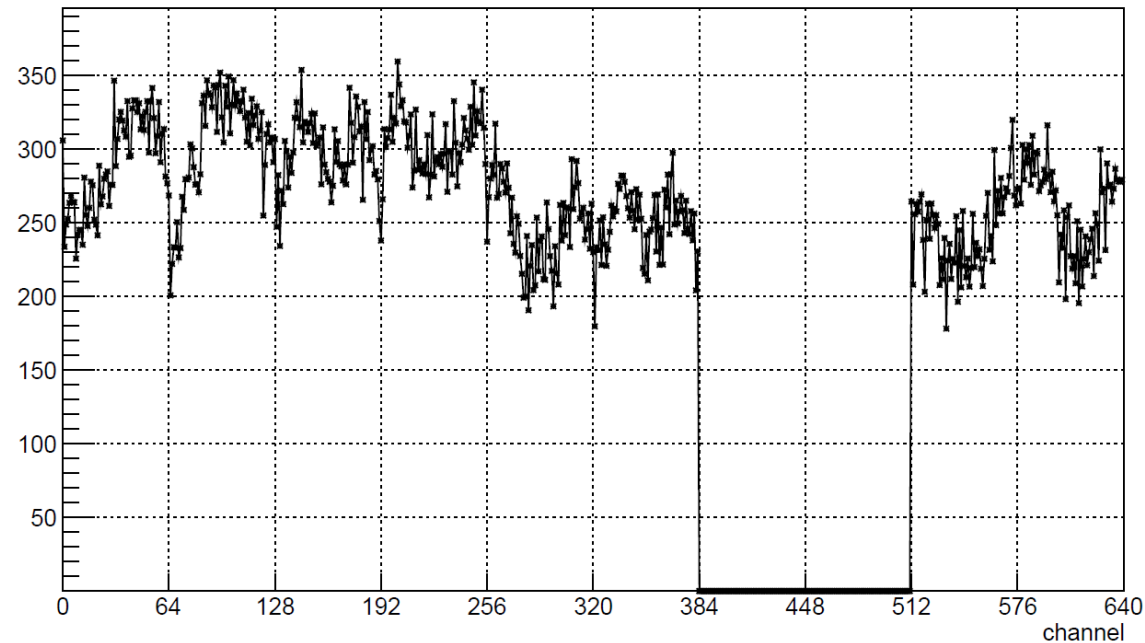
Reference: old GW

N.B.: the hole is a problem of the ADC Board

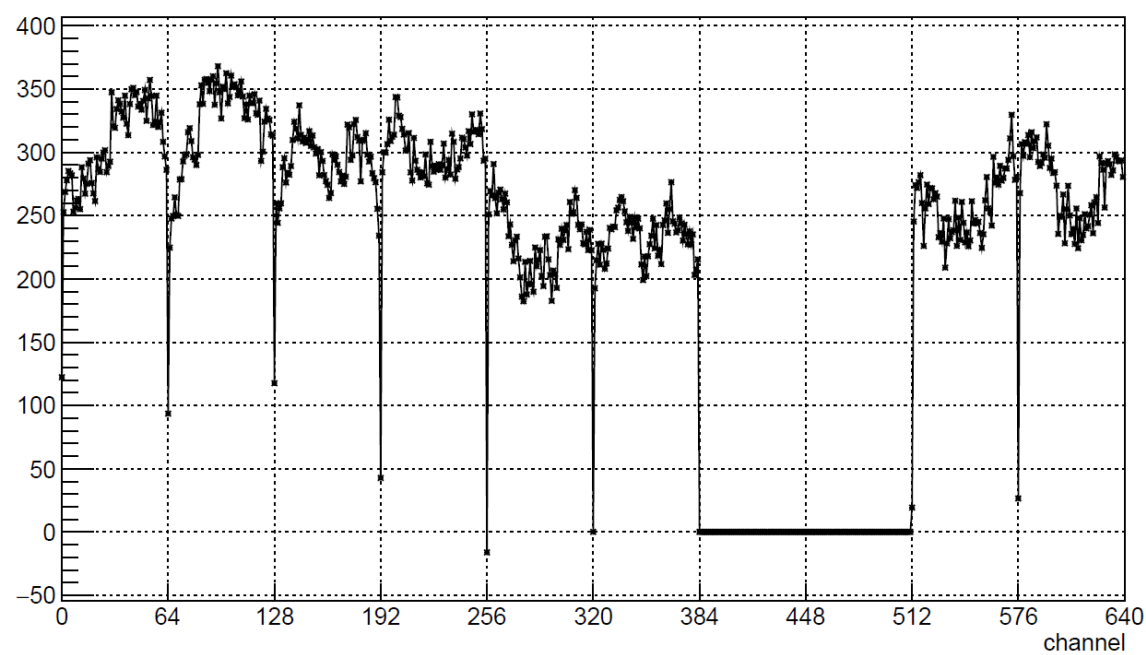
Pedestal

Sigma

Raw-Sigma

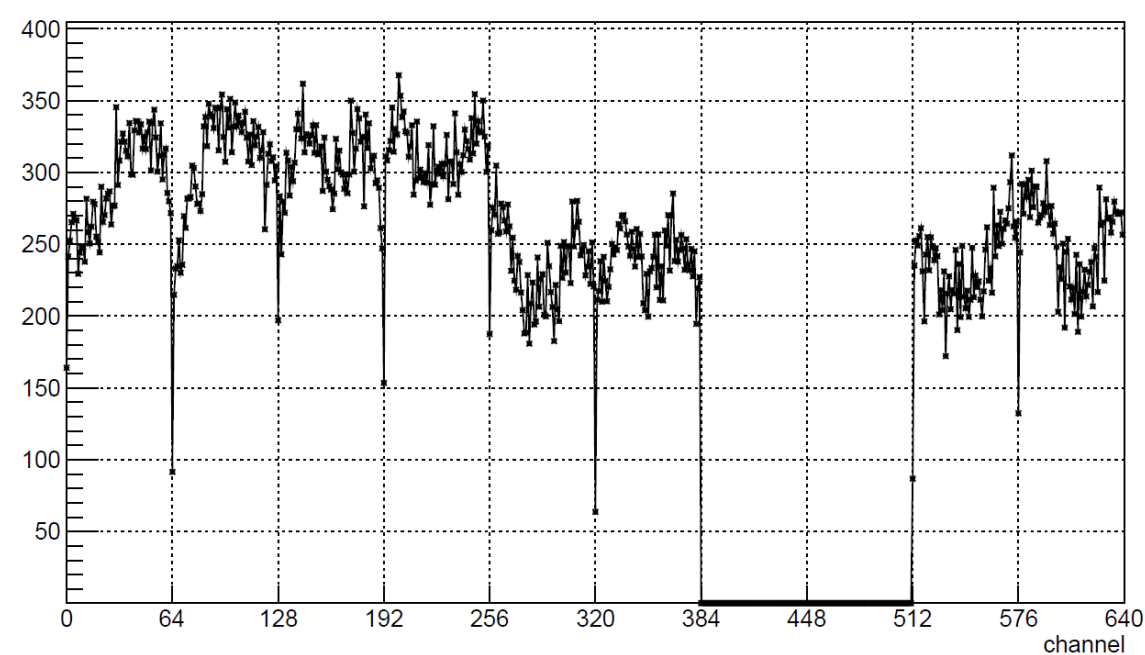
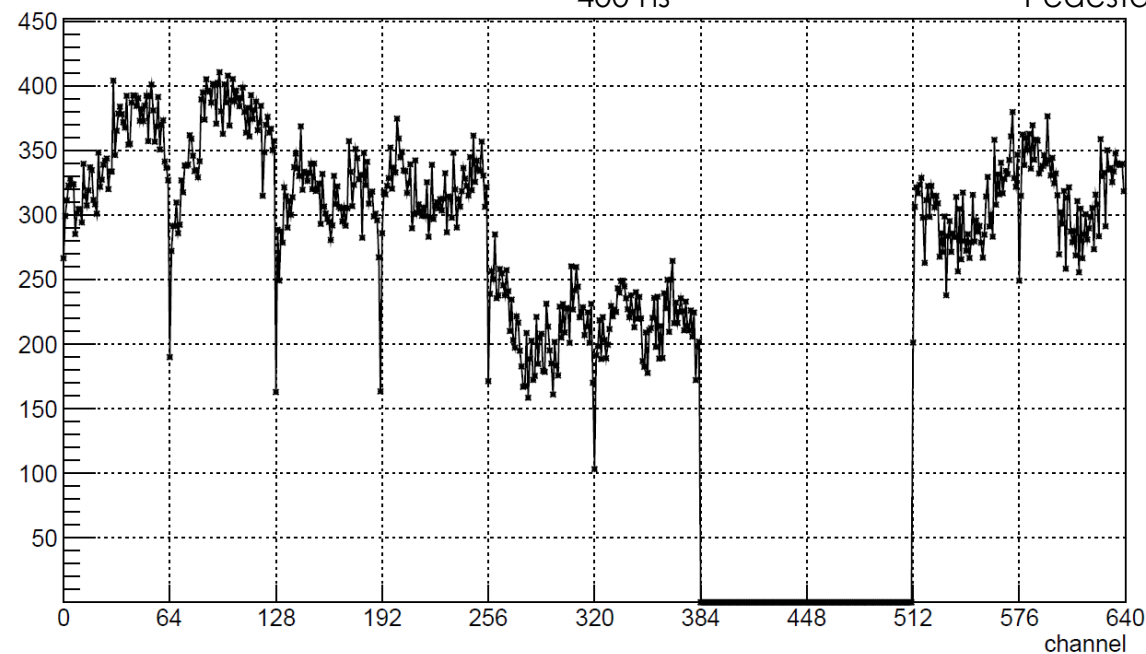


2. ADC delay Coarse Scan: Average

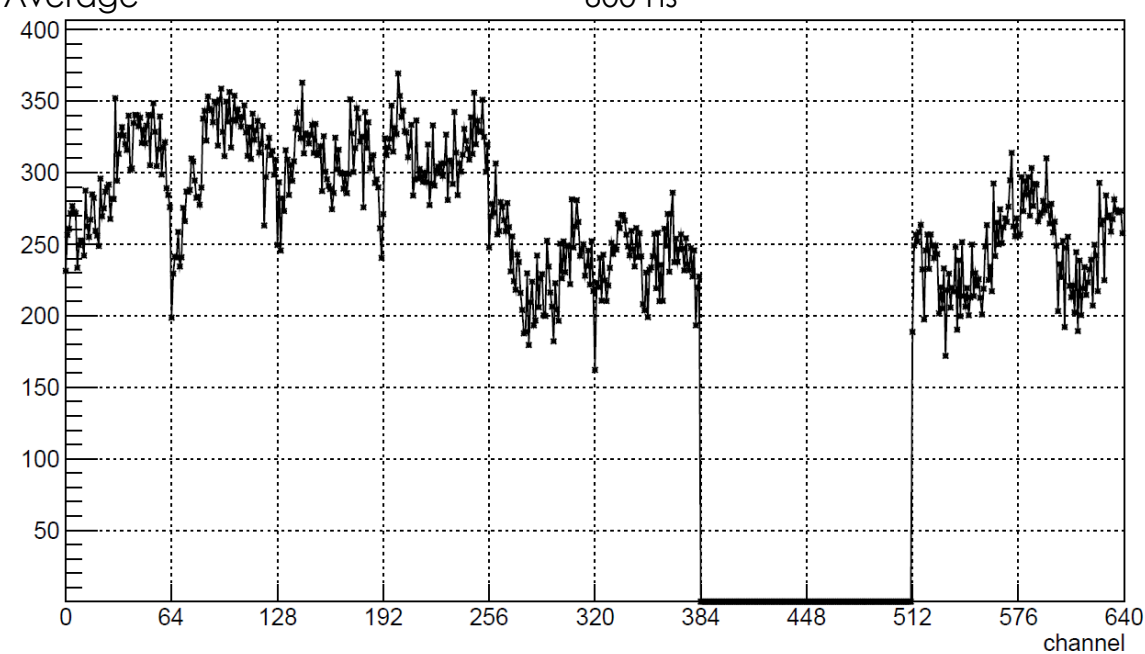


40 ns
400 ns

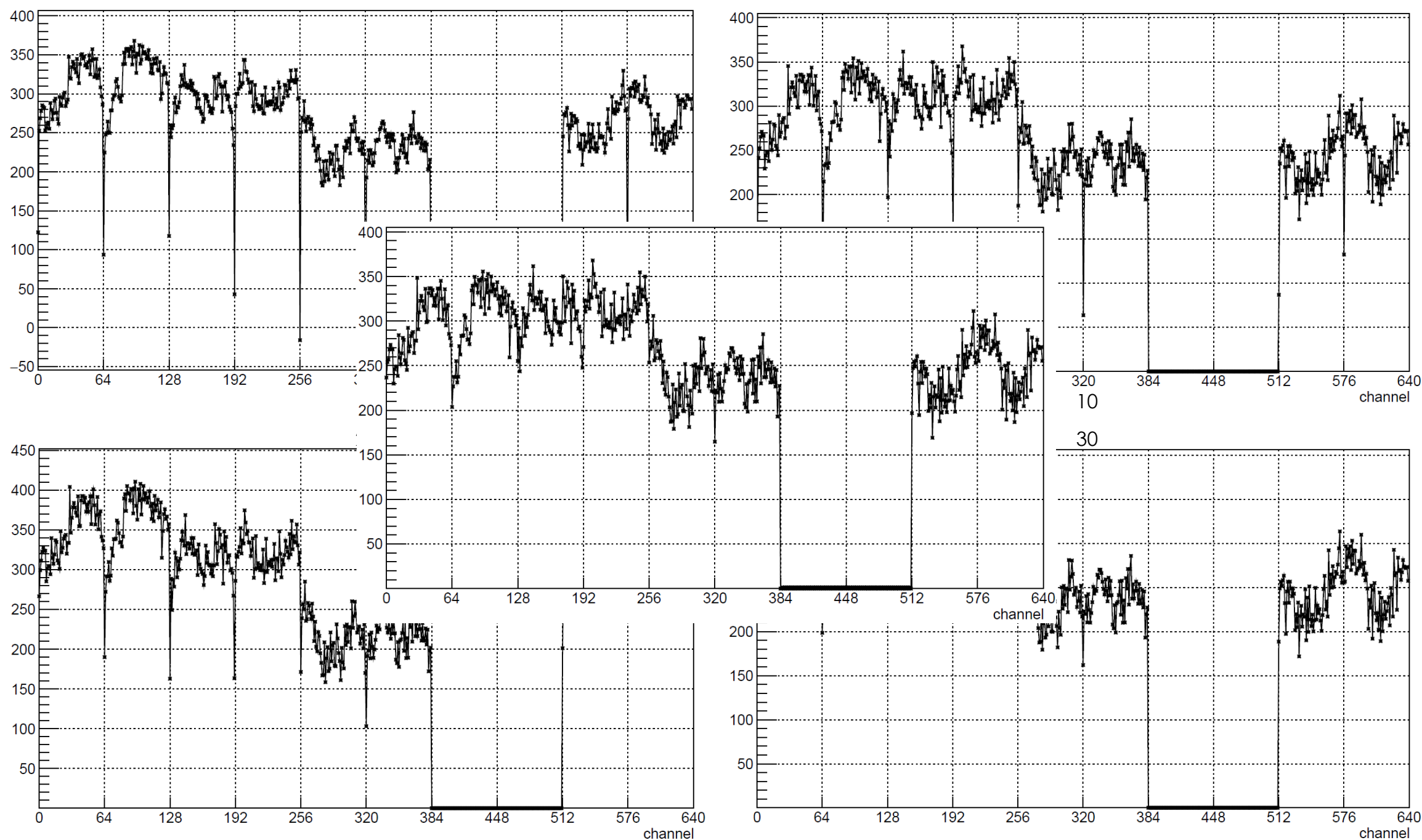
Pedestal Average



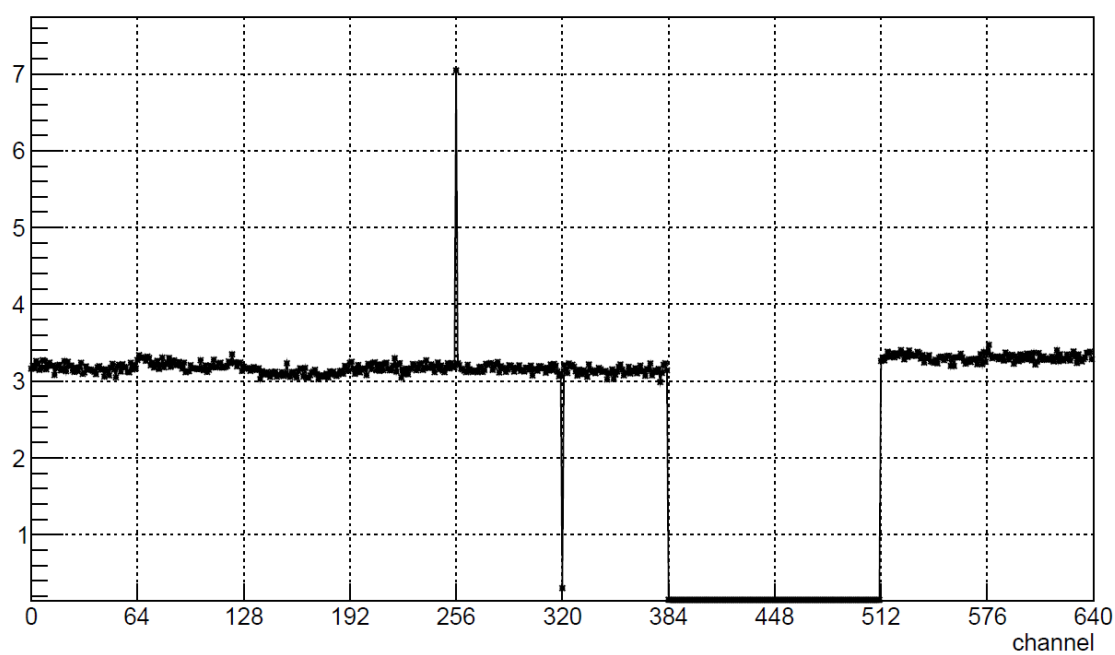
200 ns
600 ns



2. ADC delay Coarse Scan: Average

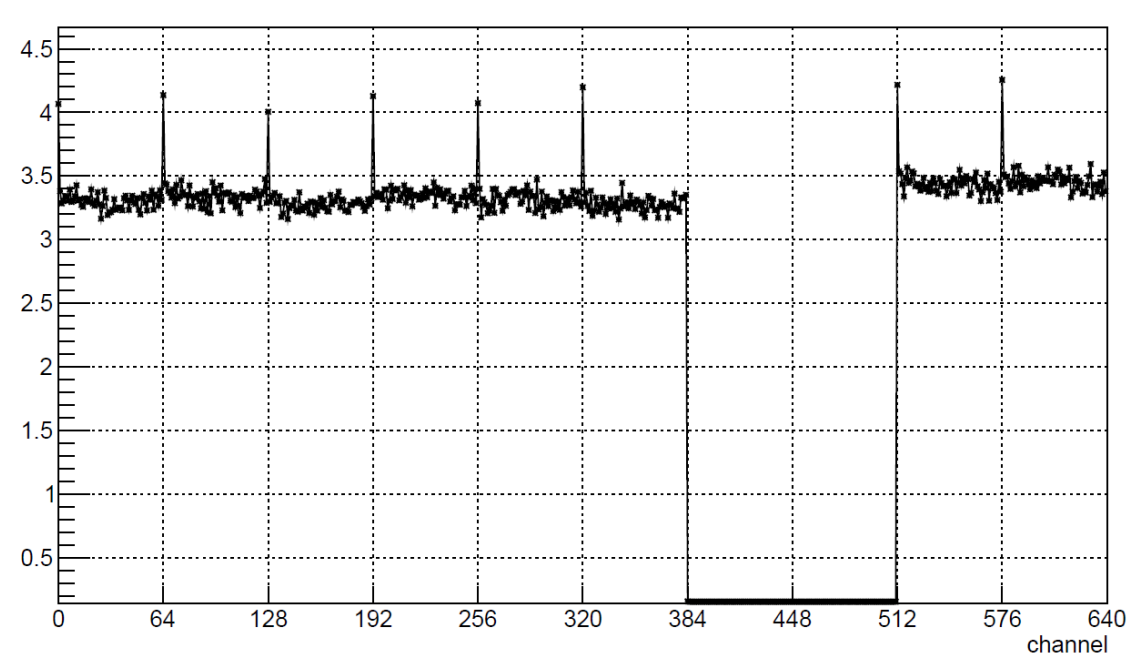


2. ADC Delay Coarse Scan: Raw Sigma

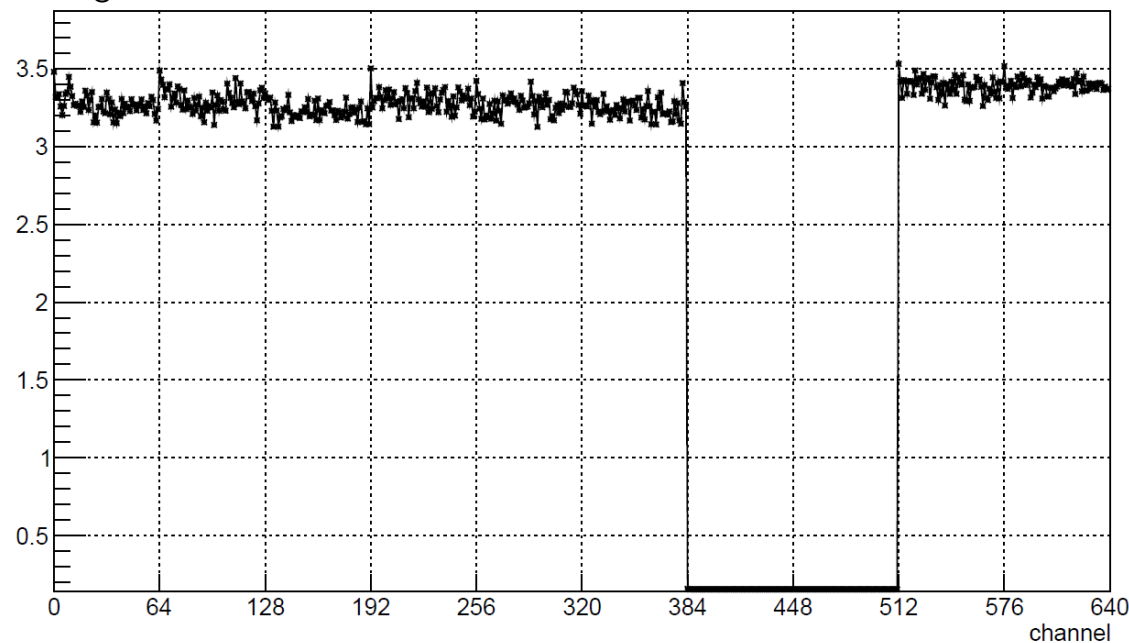
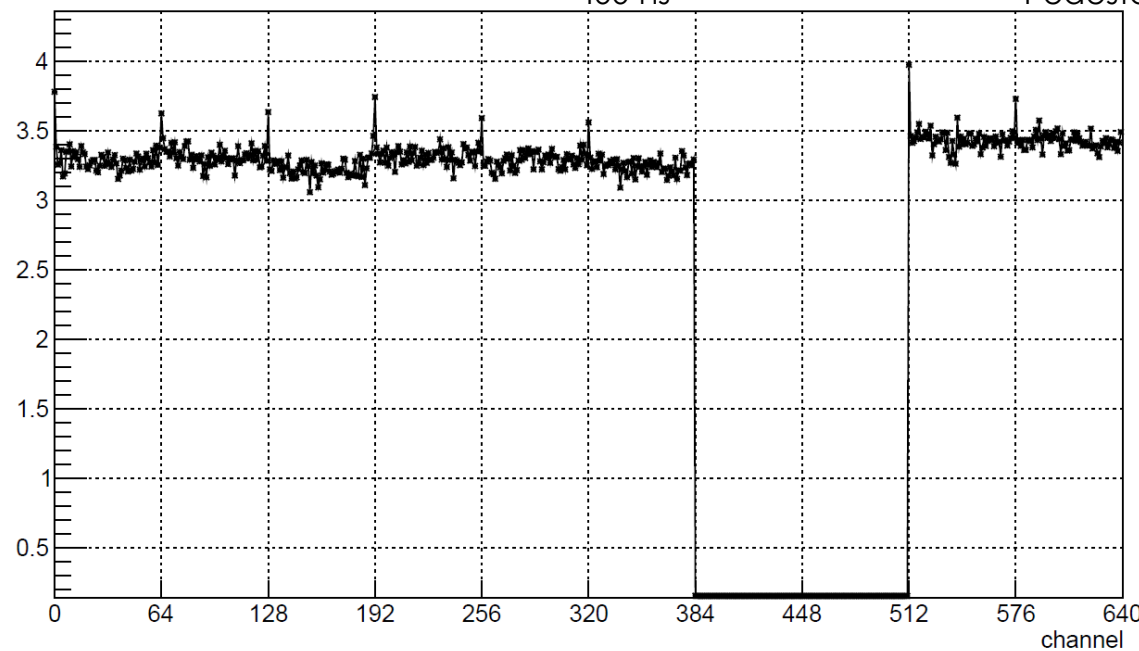


40 ns
400 ns

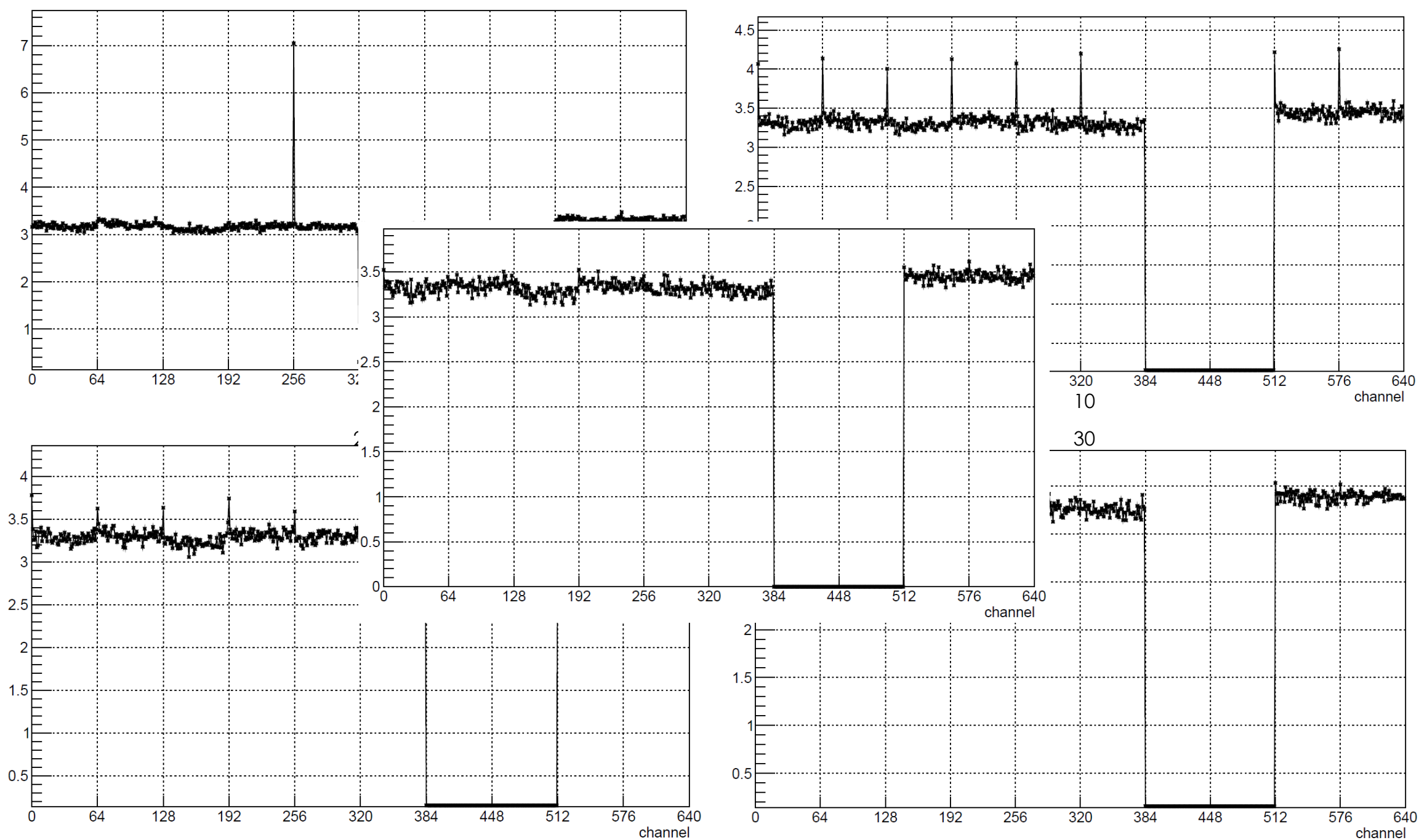
Pedestal Raw-Sigma



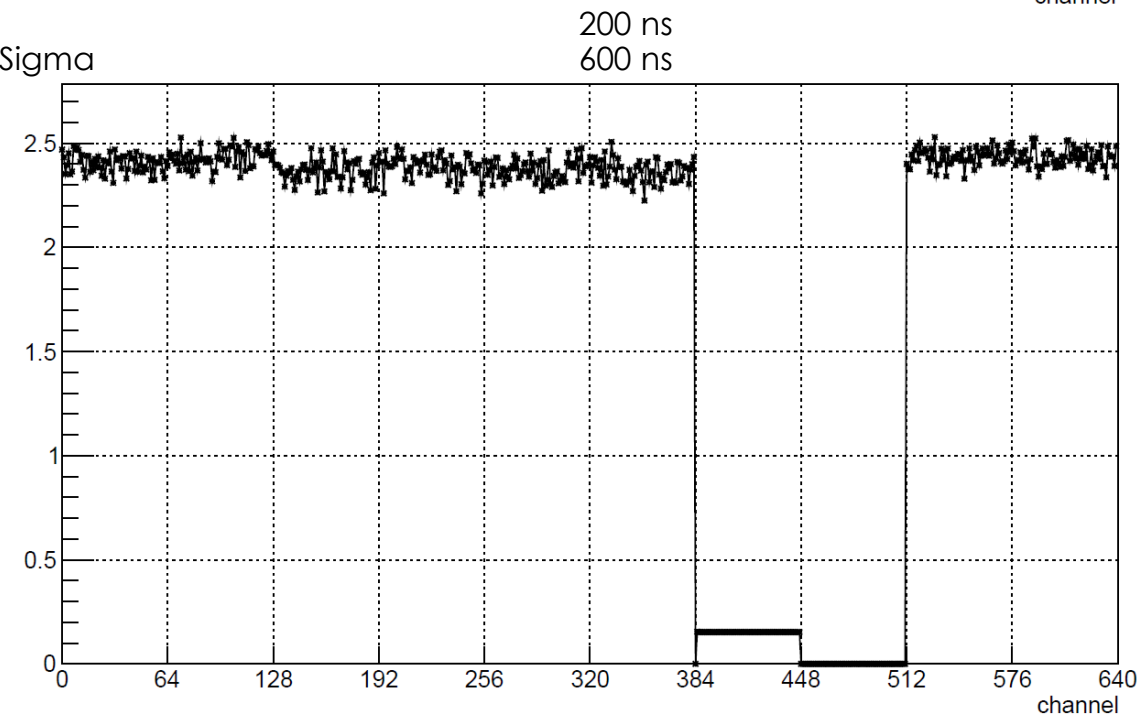
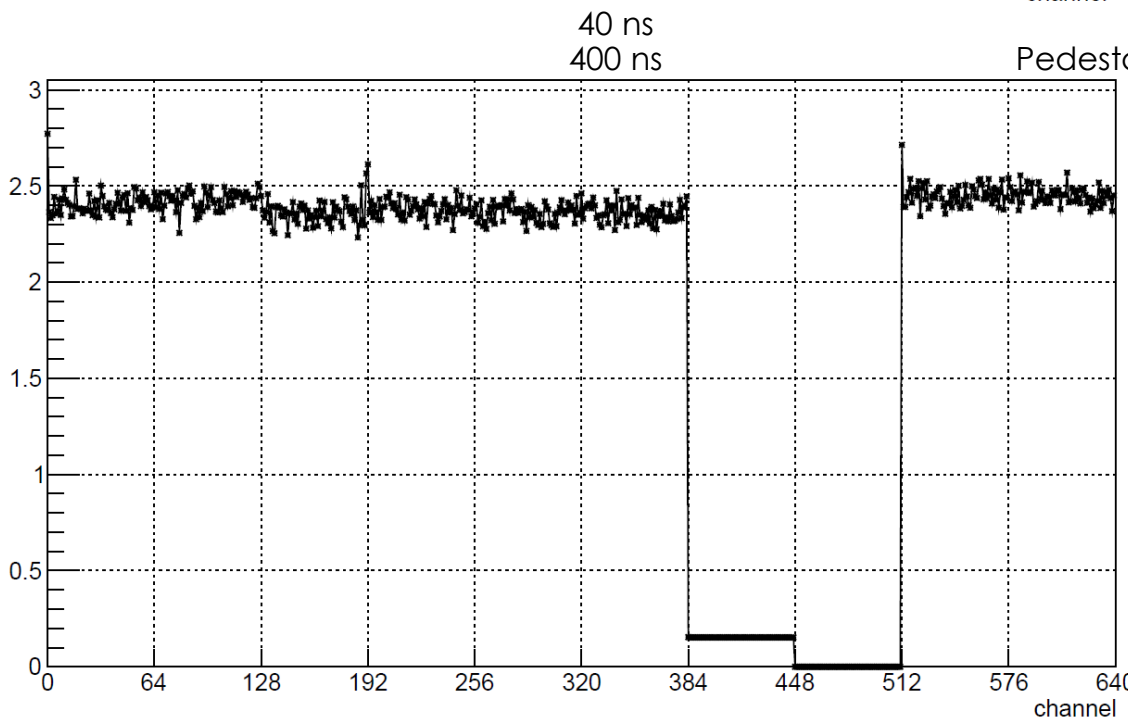
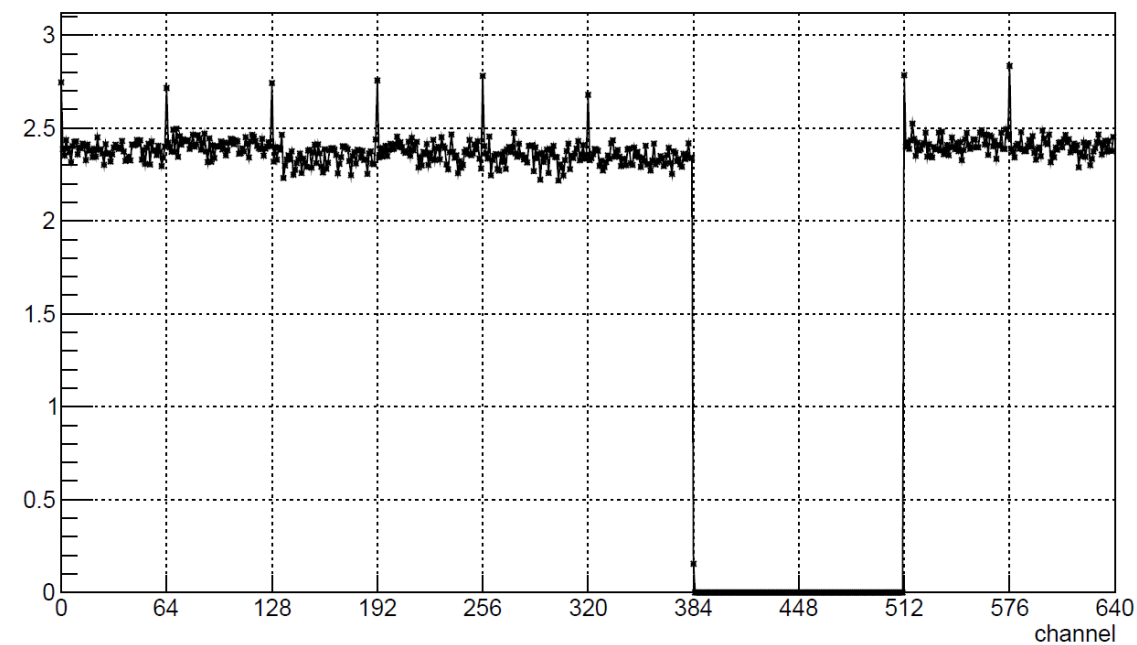
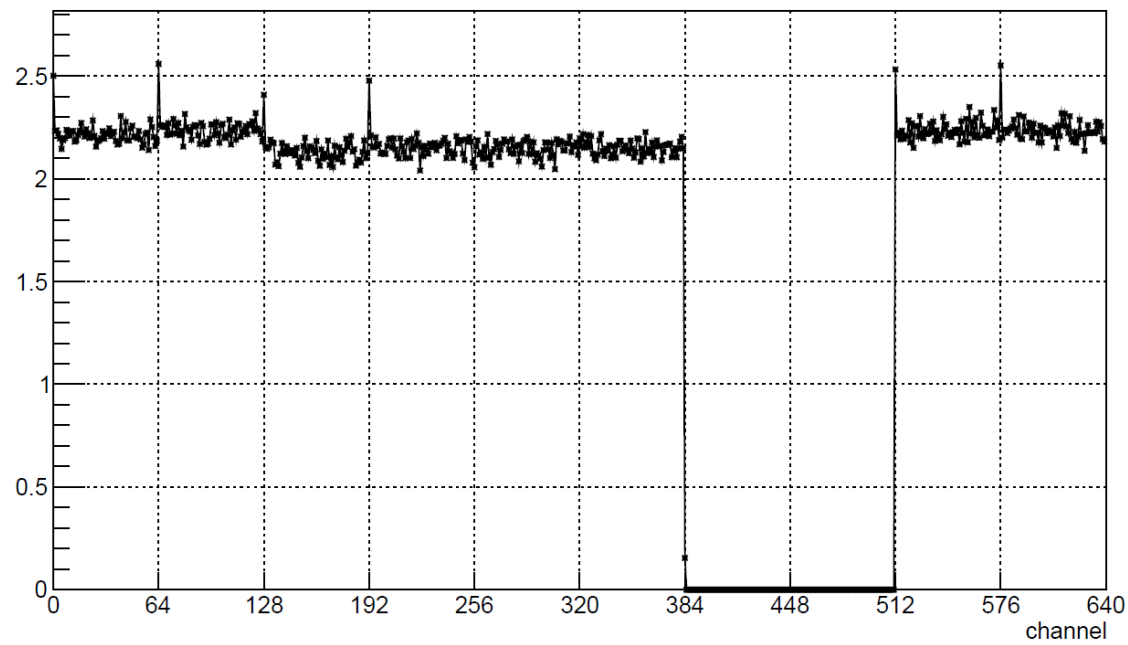
200 ns
600 ns



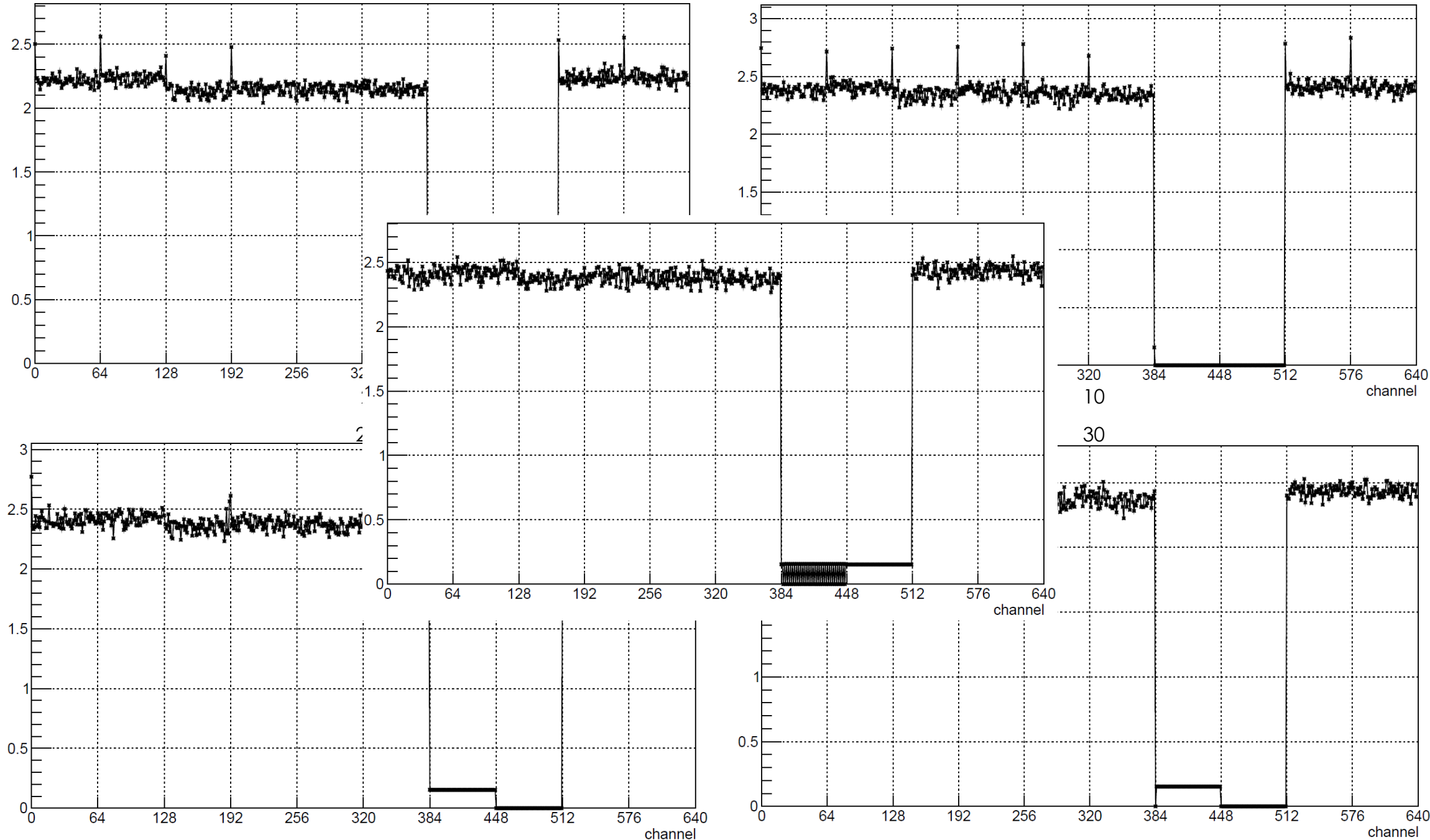
2. ADC Delay Coarse Scan: Raw Sigma



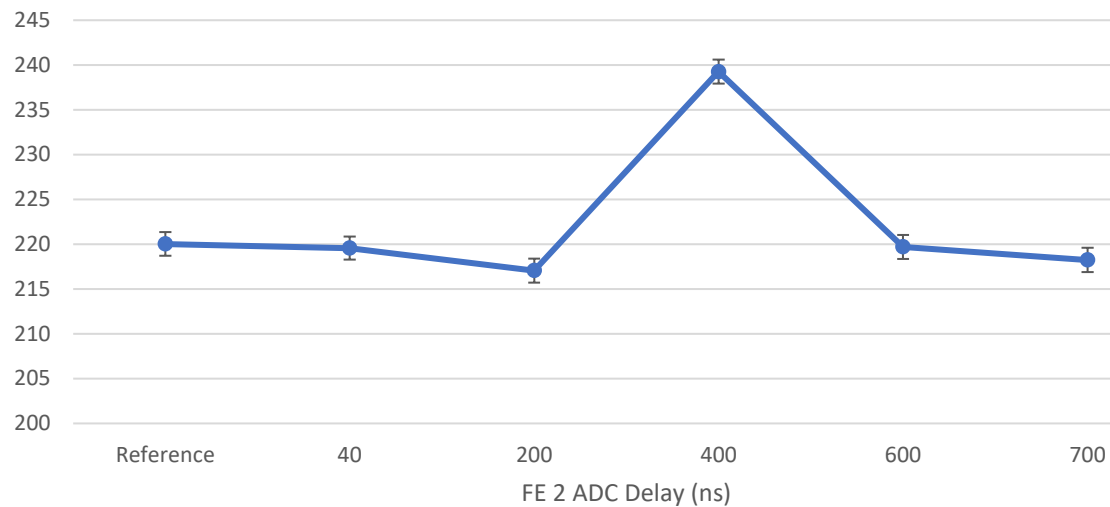
2. ADC Delay Coarse Scan: Sigma



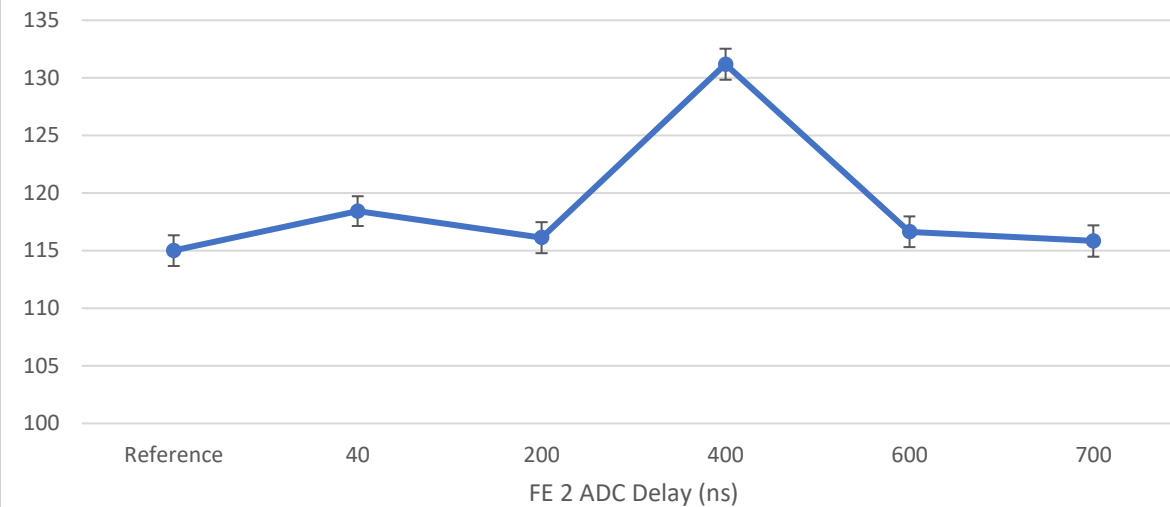
2. ADC Delay Coarse Scan: Sigma



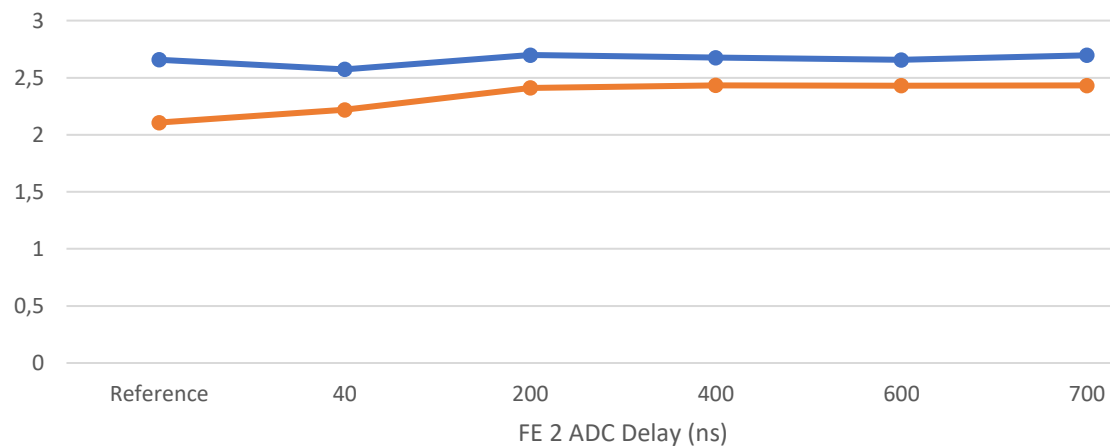
Delay scan - Pedestals Mean



Delay scan - Pedestals RMS

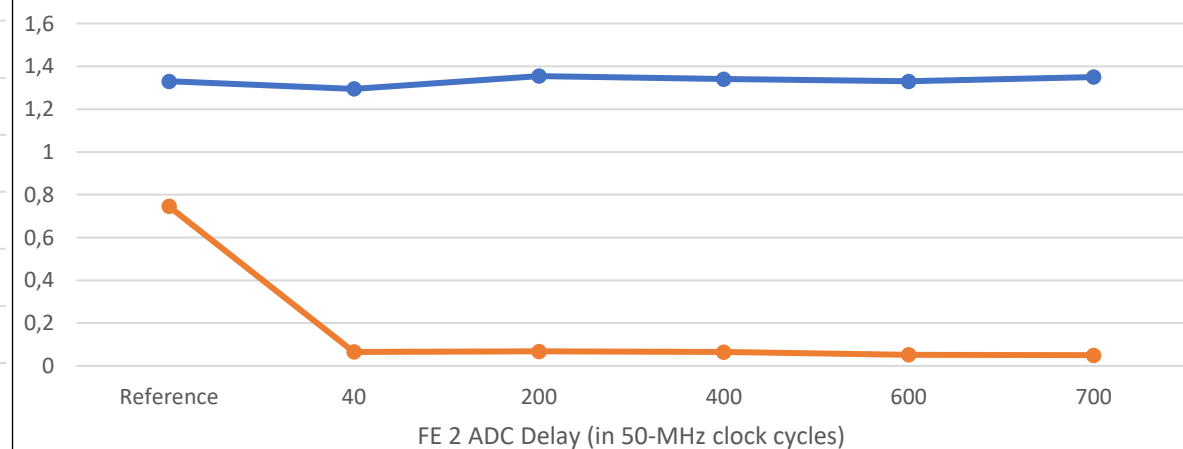


Delay scan - Raw-Sigma and Sigma Mean



Raw-Sigma Mean Sigma Mean

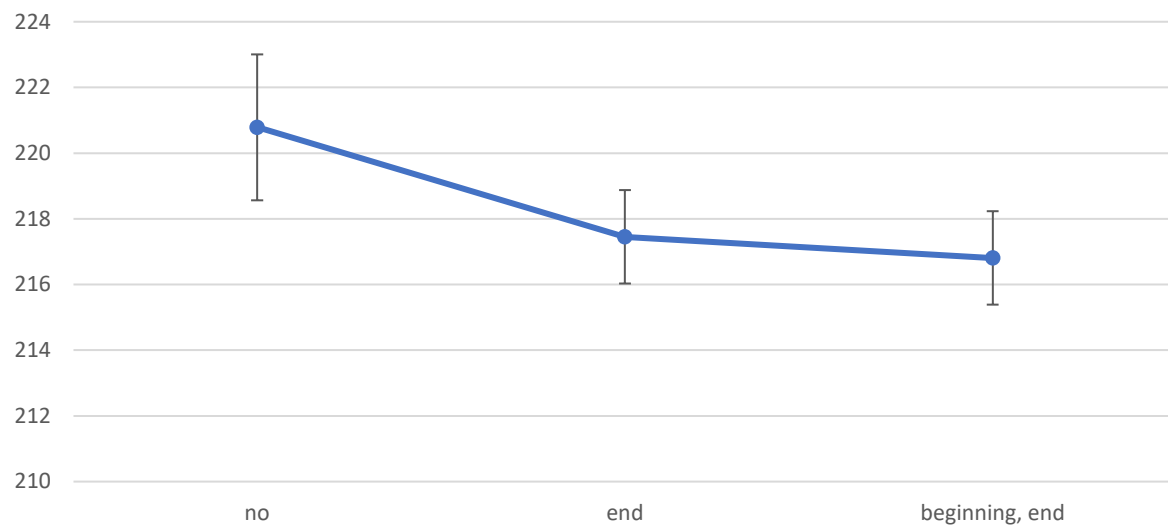
Delay scan - Raw-Sigma and Sigma RMS



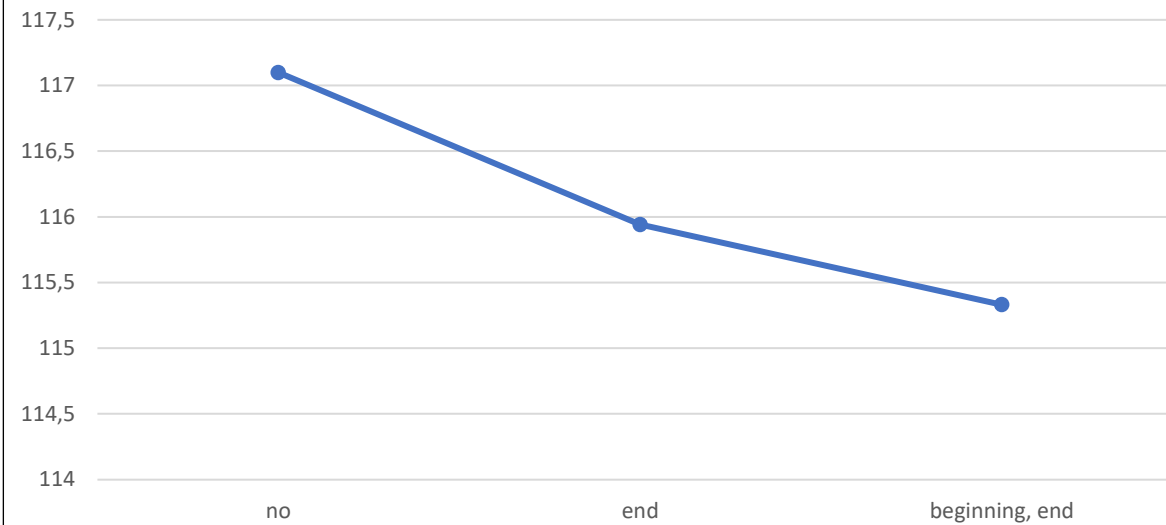
Raw-Sigma RMS Sigma RMS

3. dReset Assertion

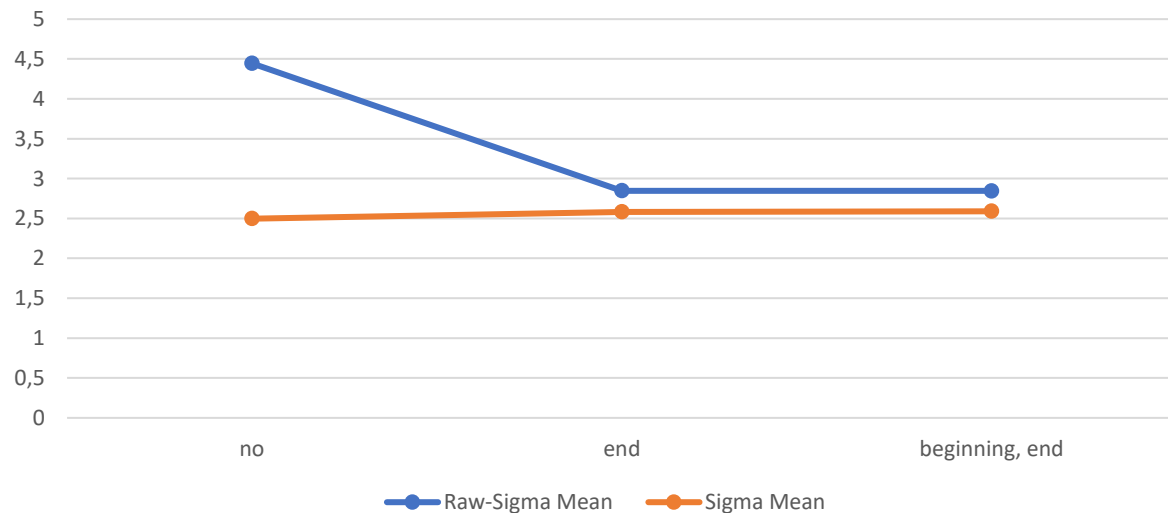
dReset Assertion – Pedestals Mean



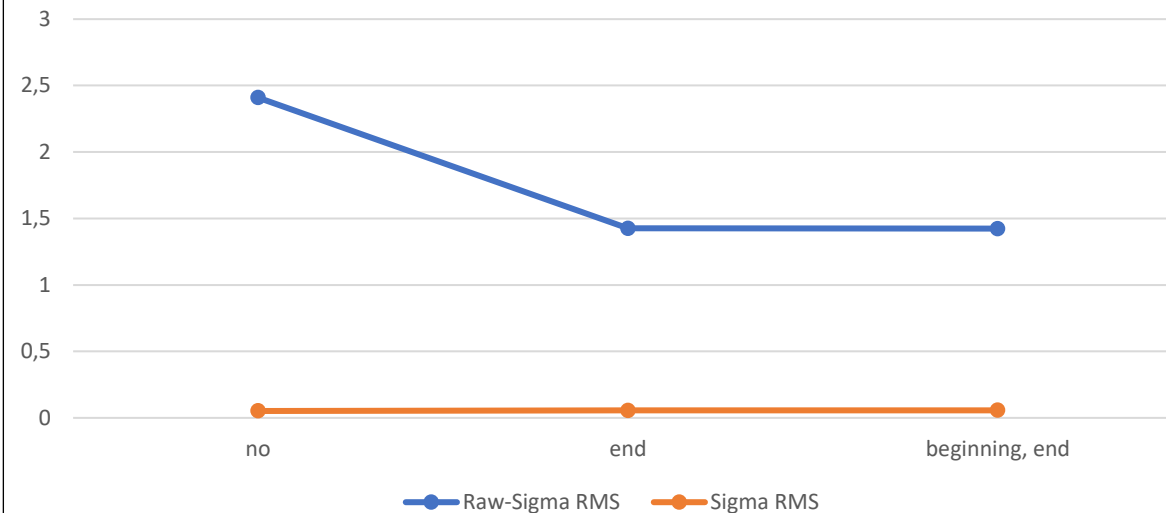
dReset Assertion – Pedestals RMS



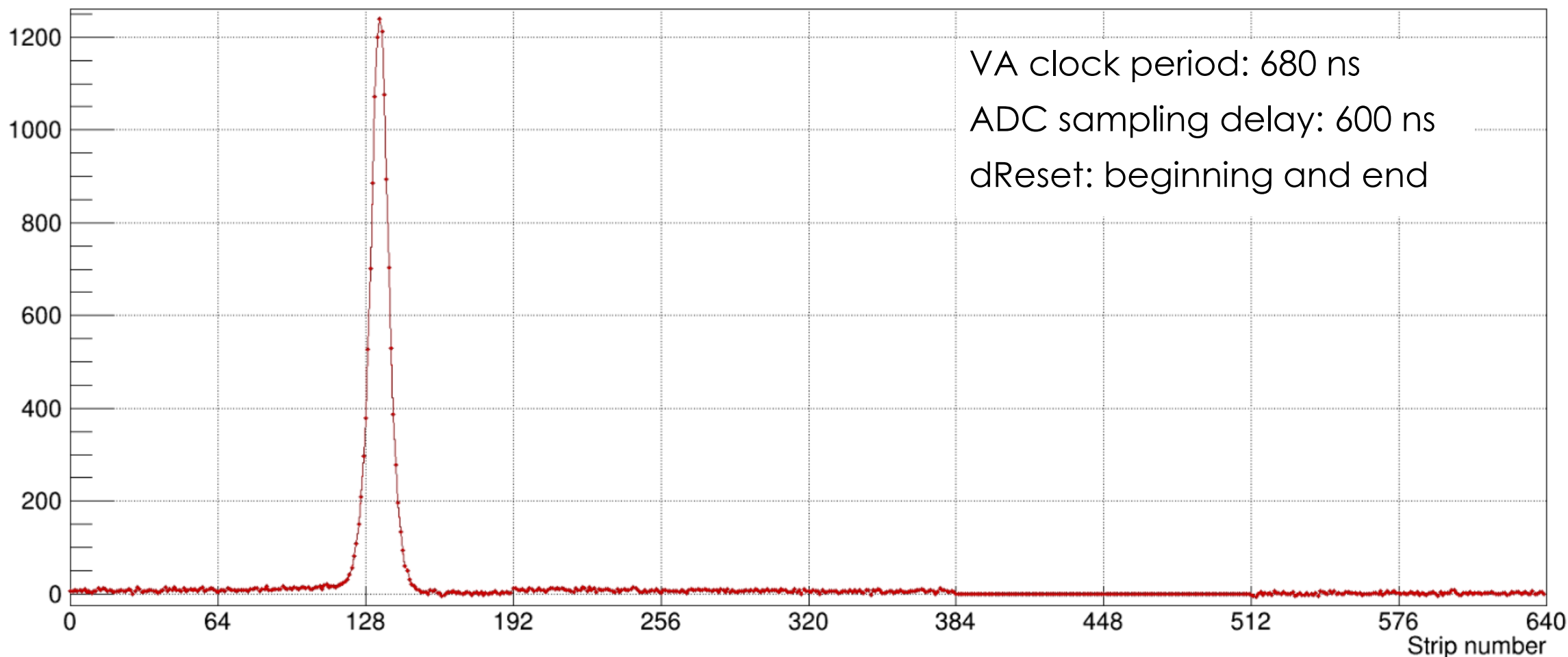
dReset Assertion – Raw-Sigma and Sigma Mean



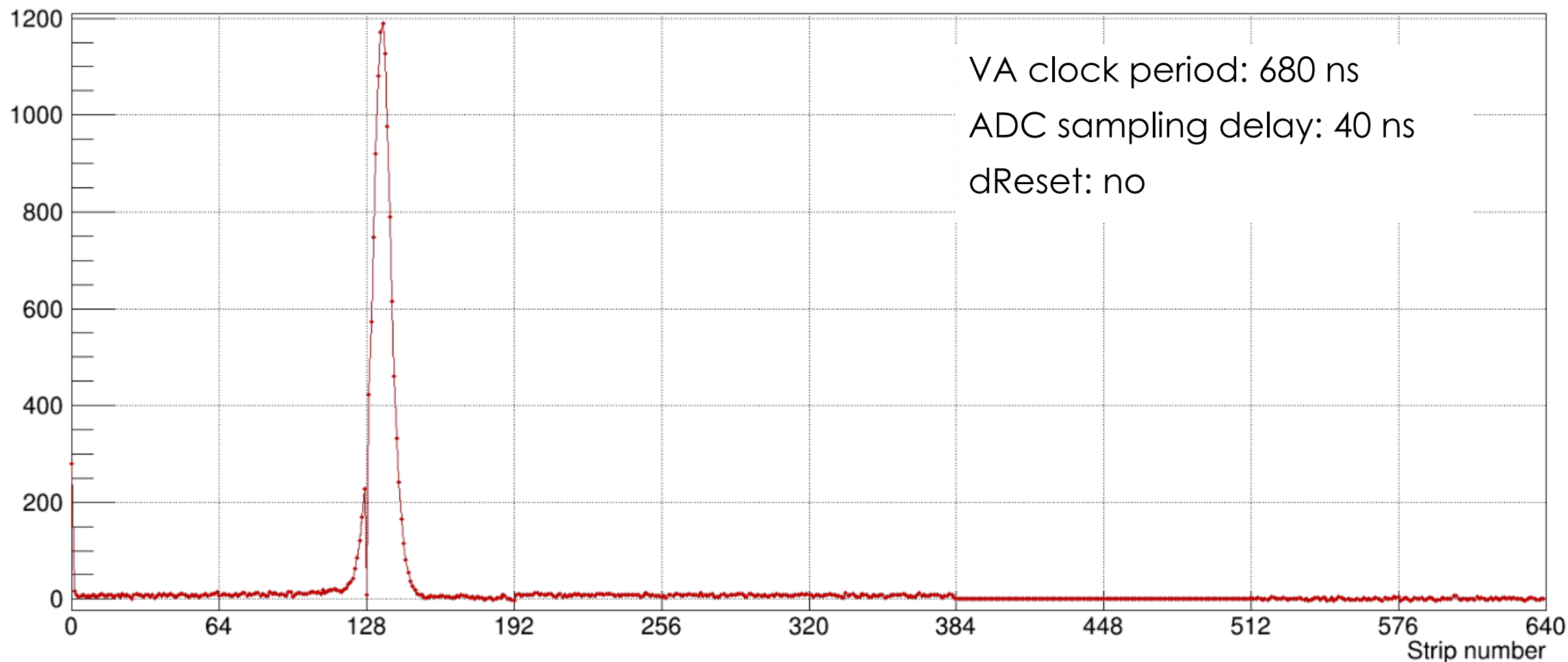
dReset Assertion – Raw-Sigma and Sigma RMS



1058 nm pulsed laser beam to see spurious signals and verify the functionality



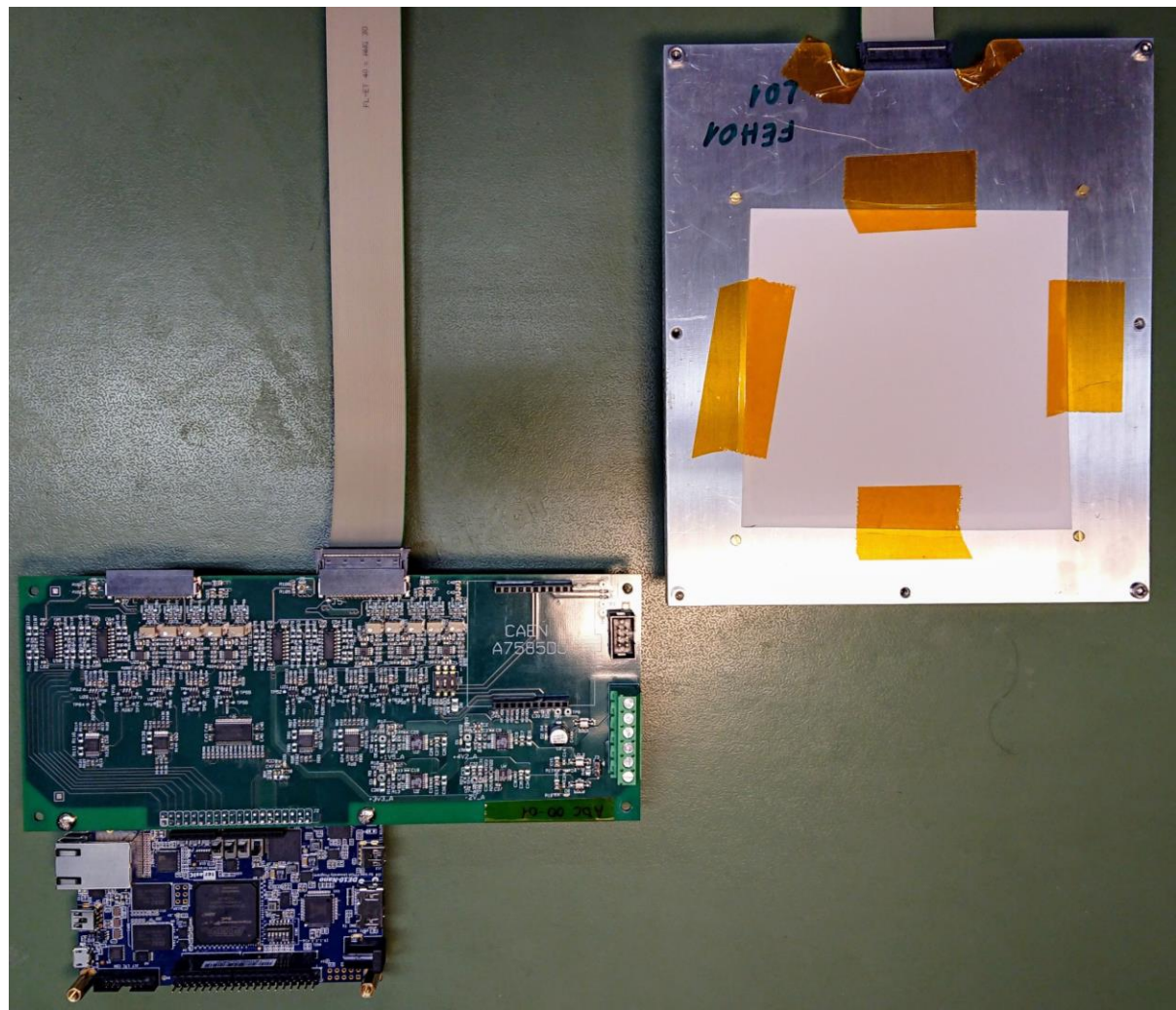
Small ADC sampling delay and no dReset (to simulate the old GW)



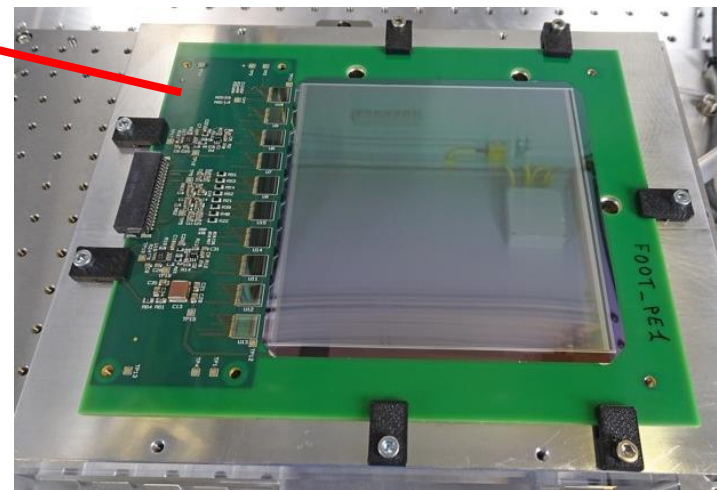
- New features implemented
 - Programmable delay between VA output and ADC sampling
 - dReset at the beginning and end of an event
 - AD7276 *Fast-mode* support
- Performed several scans to find optimal parameters
 - VA Clock: 1.47 MHz, 50% duty cycle
 - ADC Clock: 25 MHz, 50% duty cycle
 - ADC delay: 600 ns
 - 15% decrease in readout time per strip:
 - 800 ns (1.25 Msps) → 680 ns (1.47 Msps):
- No more spurious signals with laser setup

Study on last channels spurious signals

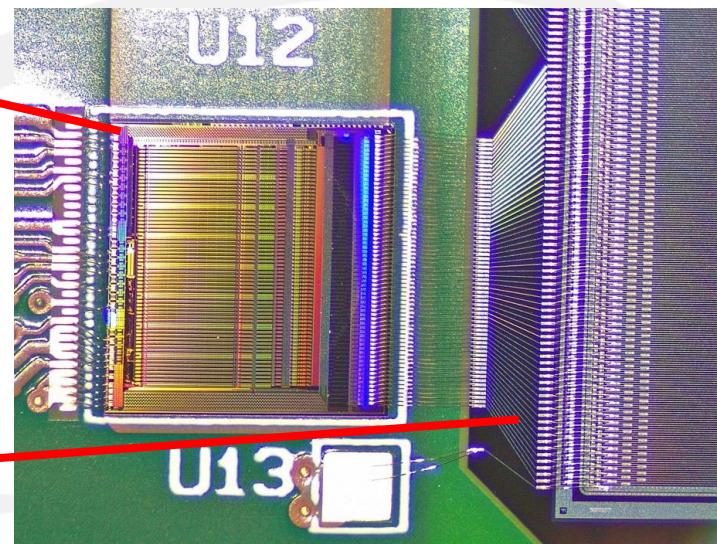
Actual setup



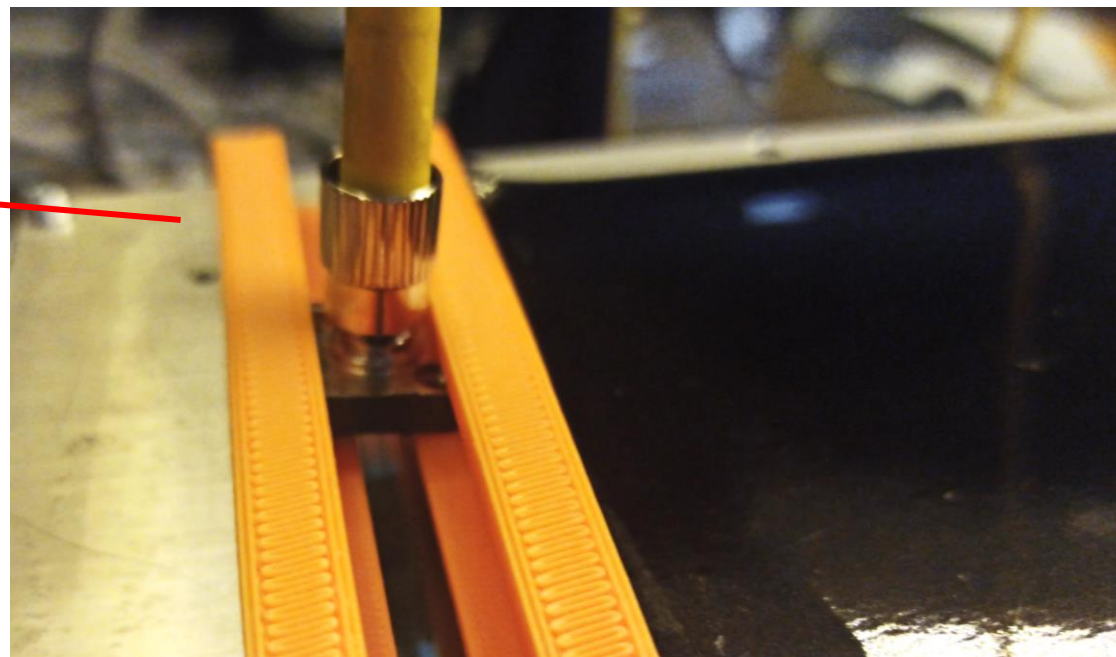
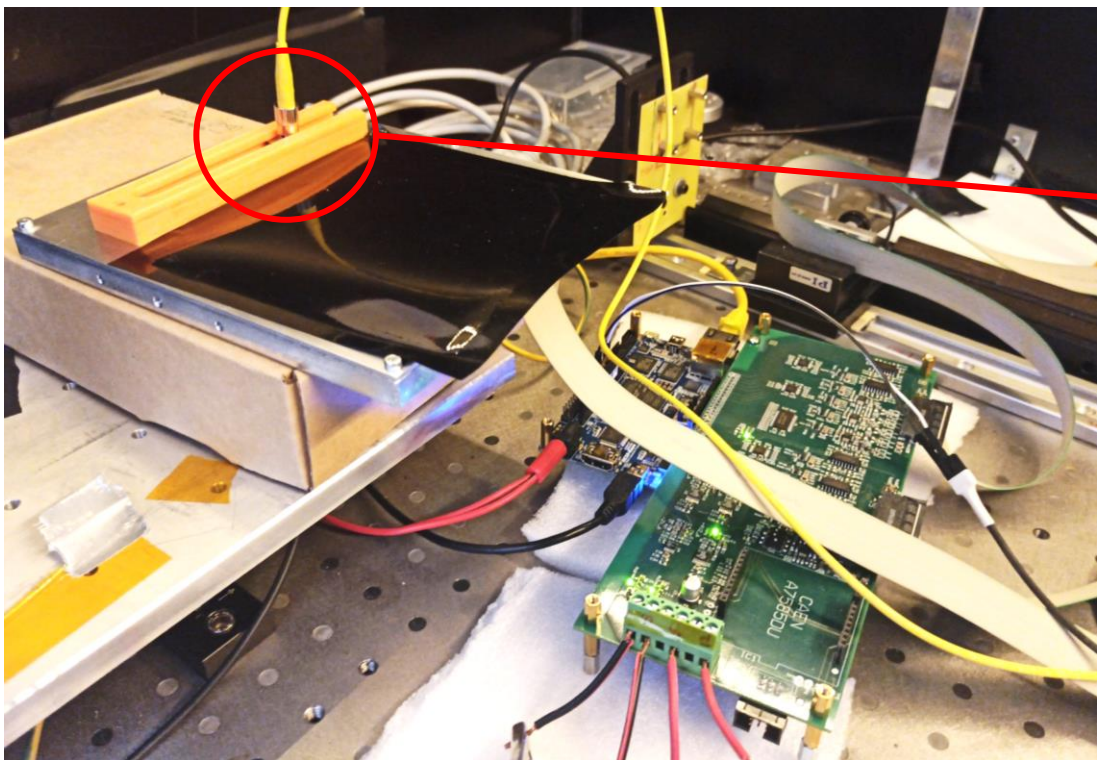
Hybrid Board



IDE1140 Front End



DET + Pitch Adapter



- μS-Modules: FOOT L13

- GW settings:

- ADC clock frequency: 25 MHz
- ADC clock duty cycle: 50%
- Artificial busy: 2.5 us

- Laser wavelength: 1058 nm

- FE clock frequency: 1.47 MHz
- FE clock duty cycle: 50%

Readout Operations: Daisy-Chain

